

secondary electron yield

in situ microanalysis

The number of secondary electrons generated per primary electron for a given specimen and experimental conditions. It depends on the (mean) atomic number of the excited area of the sample, the angle between electron beam and sample surface, the primary electron energy, thickness of the sample and sample potentials.

Source:

PAC, 1983, 55, 2023 (*Nomenclature, symbols and units recommended for in situ microanalysis (Provisional)*) on page 2026